

Amendment and Response

Applicant: Werner Ertle et al.

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Docket No.: 1431.124.101/FIN404PCT/US

Title: SEMICONDUCTOR WAFER WITH ELECTRICALLY CONNECTED CONTACT AND TEST AREAS

IN THE SPECIFICATION

Please amend the paragraph beginning on line 10 of page 11 as follows:

After testing on the test window 32, the latter is sealed with a protective layer ~~(not illustrated here)~~ 50.